# AHP-1123 Environment Test Report

Report NO: 14P020011

	Pass
Summary	🗖 Fail
	Pass with Deviation
	Comment: There are 0 temperature point marginal passed, the function is normal, hope to get
	improvement for the next generation.

Issue date	Approval	<b>Test Engineer</b>
2014-04-02	Tom Lin	Ben Sun

### **Test item list**

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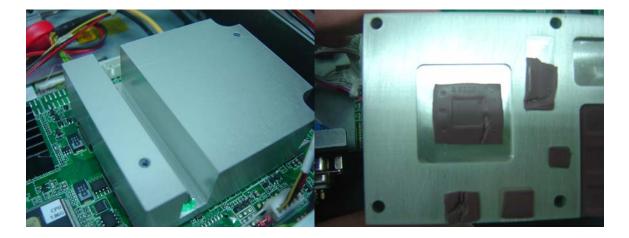
### **Testing Result**

Num	Test item list	Result	Remark
1	Temperature rise test	Pass	
2	Temperature cycle operation test	Pass	
3	High temperature storage test	Pass	
4	Low temperature storage test	Pass	
5	Humidity test	Pass	
6	Cold start and hot start test	Pass	

## **Configuration of EUT**

Num	Item	Spec
1	CPU	Intel Atom D2550 1.86GHz
2	CPU Board	GENE-CV05 B2.0.0.1
3	BIOS	GENE-CV05 R1.4
4	Memory(wide temp.)	Samsung K4B2G0846D DDR3 2GB
5	HDD	WD SATA HDD 320GB
6	Test Software	Windows 7 / Run PassMark BurnIn Test Pro 7.0

### **CPU COOLER**



**Test Date:** 03-25-2014

Test Product: AHP-1123

Test Site: AAEON QE Dept.

**Test Standard:** Refer to EN 61131-2(94), UL508 (94)

#### **Temperature Measurement:**

40 Channel Thermal Recorder: (YOKOGAWA Inc,) Model: DA100-13-1D Date of Calibration: 10/01/13 Serial Number: 12A323190

#### **Test Condition:**

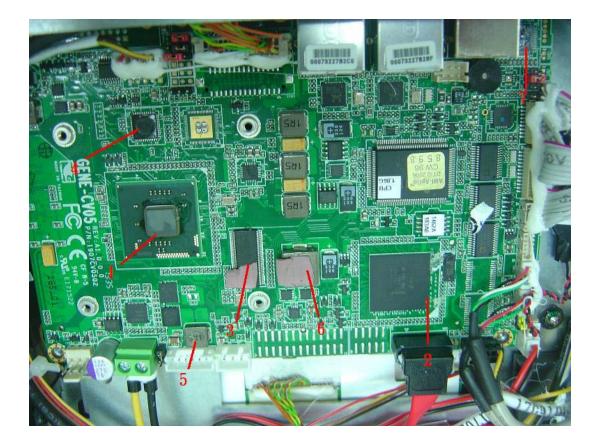
Ambient temperature:  $50^{\circ}$ C Continuous running till thermal stability (within less than  $1^{\circ}$ C)

#### **Test Software:**

Windows 7 / Run PassMark Burn In Test 7.0 Pro

#### **Terminal Recorder:**







### **Temperature rise test**

Point     Position		Describe		Tm (*2) Measured Under	Note
				<b>50</b> ℃	
1	U17	(TF)INTEL Atom N2800 CPU / 1.86GHz	100	77.9	
2	U7	(TF)NM10 Express Chipset.INTEL.CG82NM10.SLGXX	115	84.5	
3	U13	(TF)CLOCK GENERATOR.IDT.9LPRS501PGLF	95	73.7	
		(TF)Digital Video Level			
4	U31	ShifterPERICOM.PI3VDP411LSZBE	85	74.7	
5	L1	(TF)COIL.ZenithTek.ZPWM-6030M-1R5M	125	83.9	
6	L2	(TF)COIL.ZenithTek.ZPWM-1040MB-3R3M	125	75.0	
7	U42	(TF)AUDIO CODEC.REALTEK.ALC662-GR	100.5	77.1	
8	L7	(TF)COIL.ZenithTek.ZPWM-4020MP-1R0	125	87.0	
9	-	Memory chipset	95	73.9	
10		HDD Ambient Temp	60	53.7	
2. ''Tn 3. Jud	" indicates t	<ul> <li>he component's case maximum temperature value specified in its data the measured Tc value under working environmental temperature veria:</li> <li>Tm &gt; Tc; The measured value is over specification.</li> </ul>		luct specification.	<u>.</u>

It is strongly recommended to add thermal dissipation design for better reliability. :  $Tm < Tc-5^{\circ}C$ ; The measured value is with safety margin.

- Pass

### Sample Configuration & Quantity Under Test:

Quantity: 1 (AHP-1123)

#### **Test Result:**

No issues were found during the temperature rise operation test.

**Test Date:** 03-21 ~ 24-2014

Test Product: AHP-1123

Test Site: AAEON QE Dept.

**Test Standard:** Refer to IEC68-2-14 Testing procedures Test N: Change of temperature Test

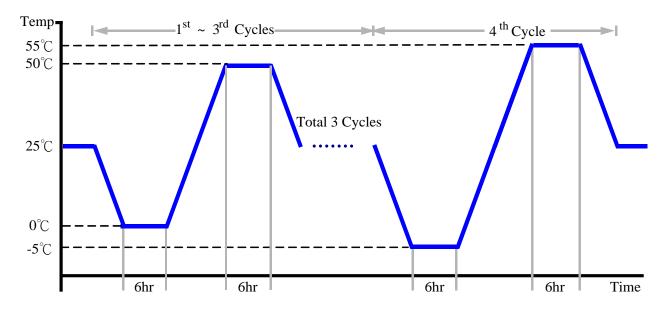
#### **Test Equipment:**

Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP.) Model: THS-D4H+-100 Date of Calibration: 10/09/13 Serial Number: 2582

#### **Test Condition:**

1. Test Low Temperature:	$0^{\circ}$ C (1~3 cycles)
	$-5^{\circ}$ C (4 <sup>th</sup> cycle)
2. Test High Temperature:	$50^{\circ}$ C (1~3 cycles)
	55°C (4 <sup>th</sup> cycle)

- 3. Test dwell time: 6Hrs
- 4. Temperature slope: 2°C/min
- 5. Test cycle: 4 cycles
- 6. Test Environment Curve:



### Sample Configuration & Quantity Under Test:

Quantity: 1 (AHP-1123)

#### **Test Result:**

No issues were found during the temperature operation cycle test.

**Test Date:** 03-19 ~ 20-2014

Test Product: AHP-1123

Test Site: AAEON QE Dept.

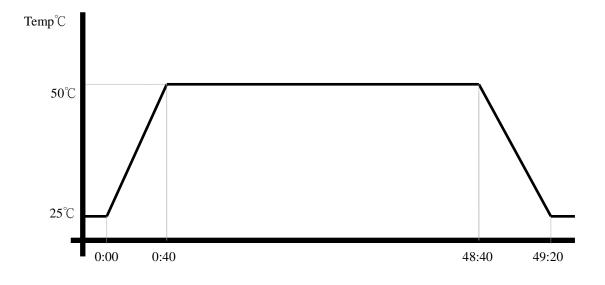
**Test Standard:** Refer to IEC 68-2-2 Testing procedures Test Bb: Dry Heat Test (Non-operation)

#### **Test Equipment:**

Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP.) Model: THS-D4H+-100 Date of Calibration: 10/09/13 Serial Number: 2582

#### **Testing Item:**

- 1. Test Temperature:  $50^{\circ}$ C
- 2. Test Times: 48Hrs
- 3. Test Software: Windows 7 / Run PassMark Burn In Test 7.0 Pro
- 4. Test Environment Curve:

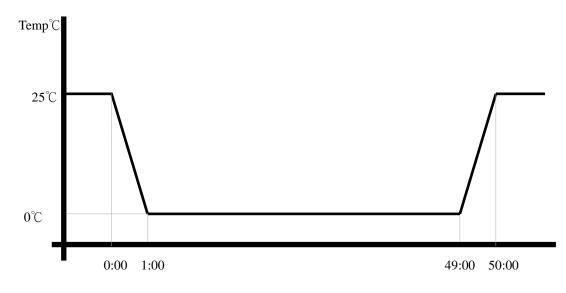


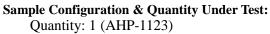
#### Sample Configuration & Quantity Under Test: Quantity: 1 (AHP-1123)

#### **Test Result:**

No issues were found after the high temperature storage test.

<b>Test Date:</b> 03-17	~ 18-2014
Test Product: AF	IP-1123
Test Site: AAEO	N QE Dept.
Test Standard:	Refer to IEC 68-2-1 Testing procedures Test Ab: Cold Test (Non-operation)
Test Equipment:	Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP.) Model: THS-D4H+-100 Date of Calibration: 10/09/13 Serial Number: 2582
Testing Item:	<ol> <li>Test Temperature: 0°C</li> <li>Test Times: 48Hrs</li> <li>Test Software: Windows 7 / Run PassMark Burn In Test 7.0 Pro</li> <li>Test Environment Curve:</li> </ol>





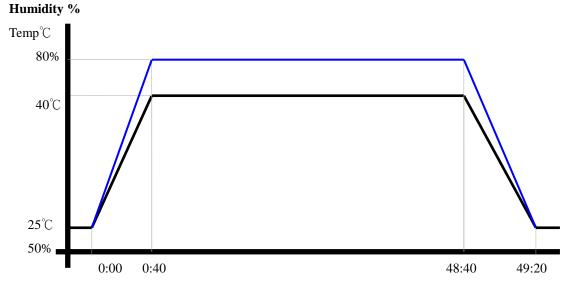
#### **Test Result:**

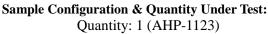
No issues were found after the low temperature storage test.

### Humidity test

Test Date: 03-13~14-2014 Test Product: AHP-1123 Test Site: AAEON QE Dept. **Test Standard:** Refer to IEC 68-2-3 Testing procedures Test Ca: Damp heat, steady state (Non-operation) **Test Equipment:** Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP.) Model: THS-D4H+-100 Date of Calibration: 10/09/13 Serial Number: 2582 **Testing Item:** 1. Test Temperature: 40°C 2. Test Humidity: 80% RH 3. Test Times: 48Hrs Test Software: Windows 7 / Run PassMark Burn In Test 7.0 Pro 4.

5. Test Environment Curve:





#### **Test Result:**

No issues were found after the humidity storage test.

**Test Date:** 03-12-2014

Test Product: AHP-1123

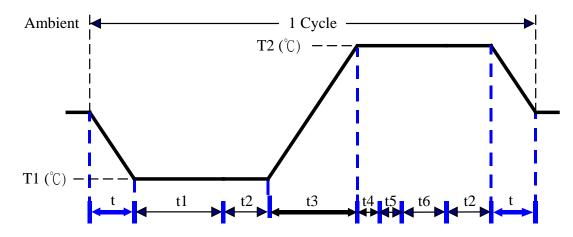
Test Site: AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-14 Testing procedures Test N: Change of temperature Test

**Test Equipment :** 

Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP.) Model: THS-D4H+-100 Date of Calibration: 10/09/13 Serial Number: 2582

#### **Test Condition:**



Parameters	Description
T1	-5°C
T2	55°C
t1	4 hrs
t2, t6	2 hrs
t4, t5	1hrs
t, t3	2°C/min
n (Cycle)	1

t = temprature slope t, t1, t6: Power Off

t2: Power on/off test 10 times (on 2 min / off 5min)

t3, t4: Run burn in test 7.0

t5: Win 7 Software restart test 3 times

Test Software: Windows 7

#### **Test Result:**

- a. No issues were found during the cold start test.
- b. No issues were found during the hot start test.